

Application/Control No.	Applicant(s)/Patent under Reexamination
09/936,742	MIWA ET AL.
Examiner	Art Unit

2814

Wai-Sing Louie

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	SEAR	CHED	
Class	Subclass	Date	Examiner
257	57,59,72,8 3,257,290, 347,351	11/15/2004	WSL
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
257/57,59,72,83,257,290 ,347,351		5/11/2005	WSL		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
LCD, alignment film, polarizer, retardation plate, reflective electrode, back light	11/15/2004	WSL
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